



Correction to: Microstructural Characteristics of Oxide Layer Growth on Tin Whisker and Finish Surface

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In the original publication of the article the sentence in the conclusions section that reads as “Both str crystalline and amorphous structures of SnO₂ were observed” should read as “Both crystalline and amorphous structures of SnO₂ were observed”.

The original article can be found online at <https://doi.org/10.1007/s42341-019-00125-7>.

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